

OX4114A-D3-1-12.800-3.3



ELECTRICAL SPECIFICATIONS

PARAMETER	SYMBOL	CONDITION	VALUE			UNIT
			Min.	Typ.	Max.	
Nominal Frequency	f_0		12.800			MHz
Supply Voltage	V_s	$V_s \pm 5\%$ @ 25°C	3.135	3.3	3.465	V
Input Current	I_s	Steady state, @ 25°C			300	mA
	$I_{s,w}$	During warm-up, @ 25°C			800	mA
Warm-up Time	t_w	V_s , nom. / $V_c=1.65V$ / $T_a=+25^\circ C$ within ± 50 ppb of final frequency with reference after 1 hours on			3	min
Frequency Calibration	$\Delta f/f_0$	$V_c=1.65V$ / @ 25°C, after 15mins power on ref. to nominal frequency and within 90 days storage.	-0.2		+0.2	ppm
Frequency Stability vs. Temperature	$\Delta f/f_0 (T_a)$	$T_a = -40^\circ C \dots +85^\circ C$, measurement referenced to 25°C	-0.01		+0.01	ppm
Frequency Stability vs. Supply Voltage	$\Delta f/f_0 (\Delta V_{CC})$	$T_a=25^\circ C$, $V_s \pm 5\%$, load=15pF	-0.05		+0.05	ppm
Frequency Stability vs. Load Change	$\Delta f/f_0 (\Delta I)$	per % load change, max.: 5%	-0.05		+0.05	ppm
Short Tem Stability		After power on 1 hour			0.05	ppb/s
Aging, after 30 days of operation	$\Delta f/\Delta t_d$	Daily	-2.0		+2.0	ppb
	$\Delta f/\Delta t_y$	First year	-300		+300	ppb
	$\Delta f/\Delta t_y$	10 years	-1.5		+1.5	ppm
Operating Temperature	T_a		-40		+85	°C
Storage Temperature	$T_{(stg)}$	Absolute max	-55		105	°C

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PHASE NOISE

PARAMETER	SYMBOL	CONDITION	VALUE			UNIT
			Min.	Typ. / Nom.*	Max.	
@1 Hz Offset	$\mathcal{E} (\Delta f)$				-70	dBc/Hz
@10 Hz Offset	$\mathcal{E} (\Delta f)$				-95	dBc/Hz
@100 Hz Offset	$\mathcal{E} (\Delta f)$				-122	dBc/Hz
@1 kHz Offset	$\mathcal{E} (\Delta f)$				-135	dBc/Hz
@10 kHz Offset	$\mathcal{E} (\Delta f)$				-145	dBc/Hz
@100 kHz Offset	$\mathcal{E} (\Delta f)$				-150	dBc/Hz

CMOS OUTPUT CHARACTERISTICS

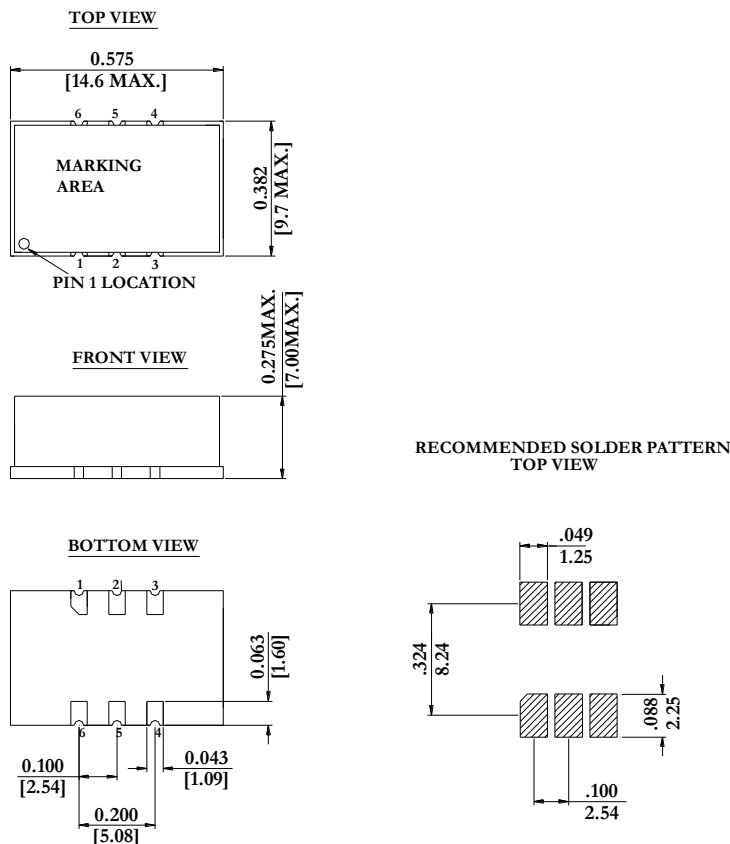
PARAMETER	SYMBOL	CONDITION	VALUE			UNIT
			Min.	Typ.	Max.	
Output Levels	VOL	$V_{CC} = 3.3V$, load = 15pF			0.4	V
	VOH	$V_{CC} = 3.3V$, load = 15pF	2.4			V
Duty Cycle	DC	load = 15pF	45	45/55	55	%
Rise/Fall Time	t_r/t_f	10% ~ 90% Vout			5	ns
Load				15		pF

ENVIRONMENTAL MECHANICAL CONDITIONS

Storage temperature range	-55°C to +105°C
Drop Test	The test shall be carried out as the provisions of the IEC60028-2-32 test Ed. 10cm height, 3 times on hard board with thickness of 3cm
Bumping Test	Device are bumped to three mutually perpendicular axes at peak acceleration of 400m/s ² , each 4000±10times, 6ms pulse duration time
Vibration Test	Frequency range: 1Hz-4Hz-100Hz-200Hz Acceleration: 0.0001g ² /Hz-0.01g ² /Hz-0.01g ² /Hz-0.001g ² /Hz Grms=1.15g Sweep time: 30 minutes (perpendicular axes each sweep time)
Mechanical Shock	100g, 6mS duration, 1/2 sine wave, 3 shocks each direction along 3 mutually perpendicular planes.
Thermal shock	0.5h@-40°C, 0.5h@+85°C, Note: the changing time < 30 seconds, cycling for 100 times

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MECHANICAL DIMENSIONS AND PIN FUNCTIONING



PIN	SYMBOL	FUNCTION
1	N/C	No connect
2	N/C	No connect
3	GND	Case/Ground
4	OUTPUT	RF Output
5	N/C	No connect
6	Vs	Supply Voltage

RALTRON	Signed	Date
Created	CP	January 21, 2019
Eng. approved	SP	January 21, 2019
REV A	Initial release	
B	CP, March 03, 2011 Updated to the current spec level	